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A Low-Latency DMR Architecture with Fast Checkpoint Recovery Scheme

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SUMMARY This paper presents a novel architecture for a fault-tolerant and dual modular redundancy (DMR) system using a checkpoint recovery approach. The architecture features exploitation of SRAM with simultaneous copy and instantaneous compare function. It can perform low-latency data copying between dual cores. Therefore, it can carry out fast backup and rollback. Furthermore, it can reduce the power consumption during data comparison process compared to the cyclic redundancy check (CRC). Evaluation results show that, compared with the conventional checkpoint/restart DMR, the proposed architecture reduces the cycle overhead by 97.8% and achieves a 3.28% low-latency execution cycle even if a one-time fault occurs when executing the task. The proposed architecture provides high reliability for systems with a real-time requirement.

key words: dual modular redundancy, checkpoint recovery, fault-tolerance

1. Introduction

Microprocessors are key components used for widely diverse applications. Processors used in safety-critical systems such as vehicles and social infrastructure must operate with extremely high reliability. Nevertheless, processors are increasingly sensitive to software errors, power supply noise, and temperature fluctuations with technology scaling. These factors engender faults in the processor. Consequently, reliable processors are being sought which can detect faults and recover from a faulty state even if faults in the processor occur.

To detect faults, Dual Modular Redundancy (DMR) with a recovery scheme has been applied to reliable processors [1]–[3]. Two cores in the DMR processor execute the same task simultaneously in parallel. The processor detects faults by comparing states of the cores (register values and stored data in the memory) at every checkpoint interval. If the states match, then the register values of the cores are copied into backup shadow registers for subsequent recovery.

If the states differ, then the cores load the shadow register values to recover the recent fault-free state. The checkpoint and recovery technique enable fault detection and recovery from a faulty state. However, the copy of register values at the checkpoint and loading of these values for recovery impose additional latency. Unless the latency is low, the technique is inapplicable to systems such as vehicle control systems. A conventional DMR architecture uses a Cyclic Redundancy Check (CRC) code for comparison and bus transfer for the copying of register values [4]. Fault-detection capabilities of the comparison of CRC code depend on the fault location. The bus transfer is processed sequentially. Therefore, the bus transfer latency increases along with the number of registers.

Several time-redundancy methods have been proposed for fault tolerant systems [5]–[6]. Although the use of time-redundancy is superior to modular redundancy such as DMR and triple module redundancy (TMR) with respect to area overhead, time-redundancy methods incur a large cycle penalty. Consequently, it is difficult to apply time-redundancy methods to microprocessors for real-time systems. Actually, DMR approaches with a recovery scheme have also been proposed [7]. However, in a recovery phase, copying for rollback must be performed via a shared bus. The latency of copying increases proportionately with the number of registers.

We propose a DMR architecture that has a low latency recovery scheme. To realize low latency, the proposed DMR architecture exploits block-level simultaneously copyable SRAM. Moreover, exploiting block-level instantaneous comparison SRAM improves the fault-detection capability. A preliminary version of this report was published earlier [8]. Compared to that earlier work, this paper includes several more evaluations to demonstrate that the proposed architecture provides benefits for real-time systems and explanation about the control flow in the proposed DMR architecture in more detail.

2. Proposed DMR Architecture with a Recovery Scheme

This section presents an overview of the proposed DMR architecture with a recovery scheme. Then the checkpoint/restart scheme is explained. Finally, we explain the differences from conventional DMR. Figure 1 portrays the proposed DMR architecture, which consists of two cores,

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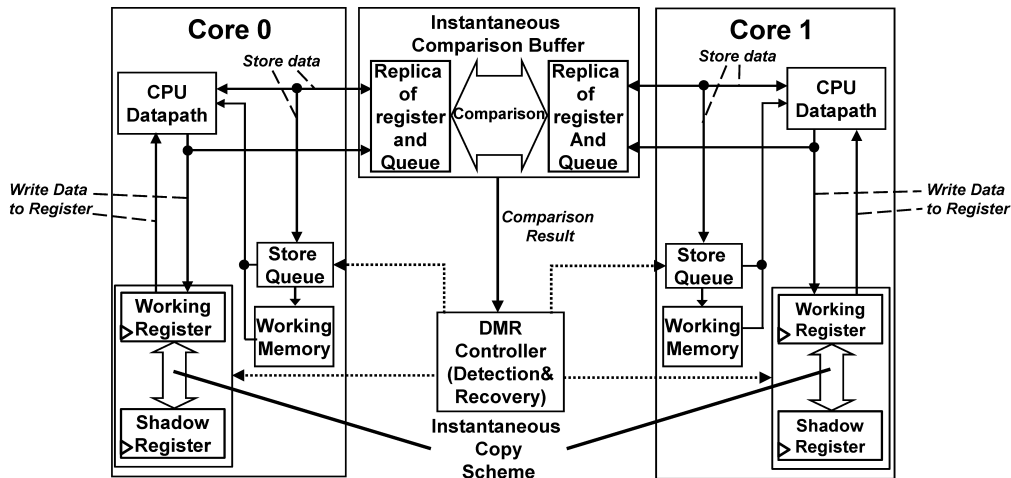


Fig. 1 Proposed DMR Architecture with recovery scheme.

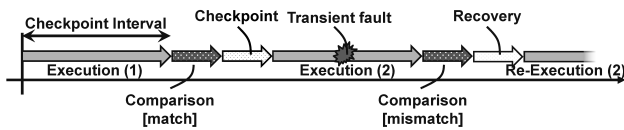


Fig. 2 Execution with checkpoint and recovery.

an instantaneous comparison buffer, and a DMR controller. The proposed architecture executes the normal operation using data stored in working memory, the store queue, and the working register. Then, store data and write data to the register are written to the store queue or the working register, and are written simultaneously in the instantaneous comparison buffer. As presented in Fig. 2, normal operations begin during checkpoint intervals. In the instantaneous comparison buffer, data of replicas of the register and queue are compared during a comparison period. Figure 3 depicts data transfer between the store queue and working memory. The store queue has a dirty bit for each block of the store queue. The dirty bit indicates whether the corresponding block of the store queue has been overwritten or not. If a datum required for a processing exists in the store queue and the corresponding dirty bit is “1,” then the datum in the store queue is used for the processing. If a datum required for a processing exists in the store queue and the corresponding dirty bit is “0,” then the datum in the work memory are used because new data should be used for processing. The comparison result is transferred to the DMR controller. If the result of the comparison indicates a match, then all the data in the store queue are written in working memory in the next normal operation (Fig. 3(a)). Data of the working register are copied in the shadow register using simultaneous data copy. The dirty bits remain unchanged. If the result of the comparison indicates a mismatch, then the store queue data are erased and the data of the shadow register are transferred to the working register (Fig. 3(b)). Dirty bits are set to “0” because the possibility exists that faults occur in the store queue. Then the process restarts from the latest checkpoint.

Conventional copying between the working register

and the shadow register is executed via the shared bus, but latency rises proportionately to the number of registers. Moreover, normal comparison of data between the dual cores is performed via the bus, so latency increases along with the data size. Although a comparison of CRC is also often used to reduce the number of comparison cycles, CRC might be unable to detect multi-bit error.

The proposed architecture is effective for a transient fault such as soft error and a read/write failure in a SRAM cell. However, a permanent fault cannot be covered because this architecture will repeat fault detection and recovery during execution if a permanent fault occurs. In some cases, a transient fault causes an infinite loop. For example, when a comparison result indicates a mismatch and a transient fault occurs at the flip-flop in the DMR controller, this architecture will perform an infinite loop. However, the probability that a transient fault occurs in DMR controller and the comparison result indicates that a mismatch is extremely low.

3. Instantaneous Comparison and Simultaneous Copy

The proposed DMR architecture exploits SRAM with simultaneous copy and compare functions. Herein, we explain the instantaneous comparison and the simultaneous copy scheme.

A. SRAM with Simultaneous Copy and Compare Function

Figure 4 presents a schematic of a pair of 6T bitcells, which realize a simultaneous copy scheme and the instantaneous comparison function [11]. The pair of 6T bitcells mutually connects their internal nodes using pMOS transistors. The area overhead of the bitcell is greater than that of the conventional 6T bitcell by 11%.

B. Instantaneous Comparison

The instantaneous comparison can be explained using

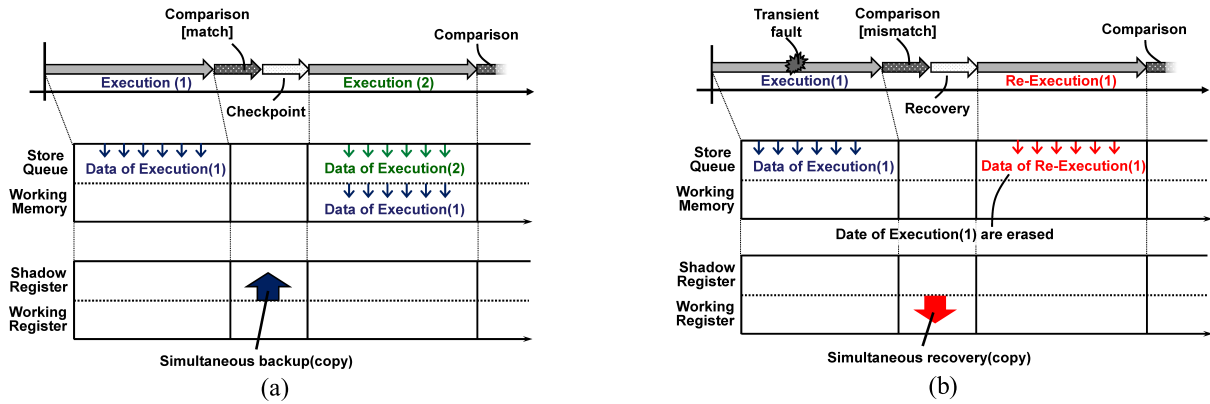


Fig. 3 Date between Store Queue and Working Memory: (a) comparison match and (b) comparison mismatch.

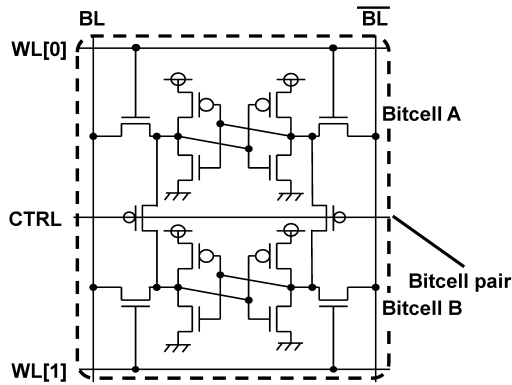


Fig. 4 Schematic of SRAM.

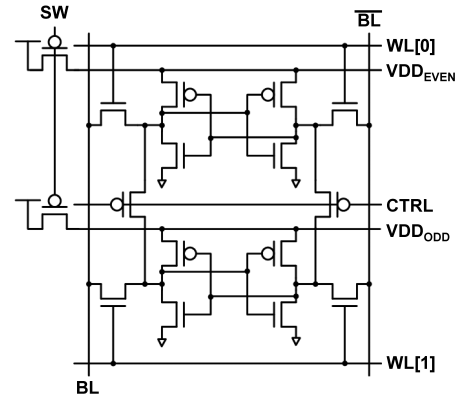


Fig. 5 Instantaneous comparison feasible 6T bitcell pair.

Fig. 5. In comparing data, the connecting pMOSes are turned on by lowering the CTRL signal [9]. If a 6T bitcell pair retains different data, then the supply current flows into a ground. However, if it retains the same data, then the supply current does not draw through a bitcell pair because no current path exists. A comparison is made instantly among all 6T bitcells pairs. The instant comparison is presented in [9]. It takes four cycles to realize an instantaneous comparison independent of the size of the comparison buffer. The cycle overhead by normal comparison via the shared bus lengthens as the number of registers increases. Although comparison with the CRC can accomplish comparison in two cycles, the instantaneous comparison scheme consumes 99.79% less energy than comparison with a CRC comparison circuit because no complex calculation is required for the instantaneous comparison [10]. However, the shortcoming of this comparison scheme is that area overhead increases according to the size of the instantaneous comparison buffer.

C. Simultaneous Copy Scheme

The simultaneous copy scheme is extremely effective for the reduction of latency for the checkpoint and recovery state. Figure 6 depicts the simultaneous copy scheme between the working register and a shadow register. The process of copy between 6T bitcell pair is explained in [10] in detail. The

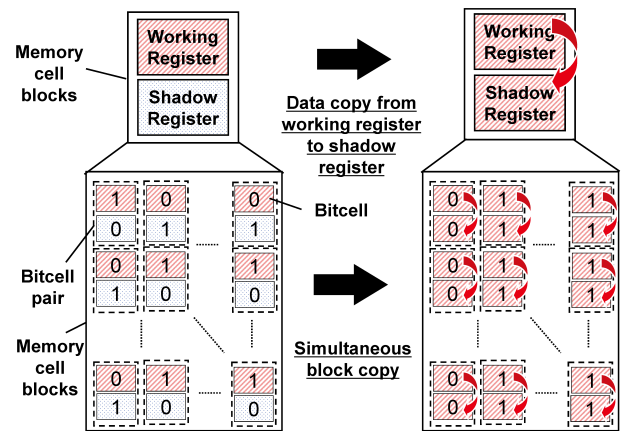


Fig. 6 Simultaneous copy scheme.

checkpoint data can be backed up or restored simultaneously using no shared bus, but all 6T bitcell pairs. Consequently, the proposed SRAM structure requires only four cycles irrespective of the size of registers for the simultaneous block copy.

4. Simulation Results

4.1 Cycle Penalty Attributable to the Checkpoint Recovery Approach

The evaluated cycle overhead in the DMR phase is presented in Fig. 7. The DMR phase is defined as the period of comparison and copy between registers for the checkpoint recovery approach. Automotive embedded processors, used for a real-time system such as a engine control and a airbag system, are designed to integrate register banks. Assum-

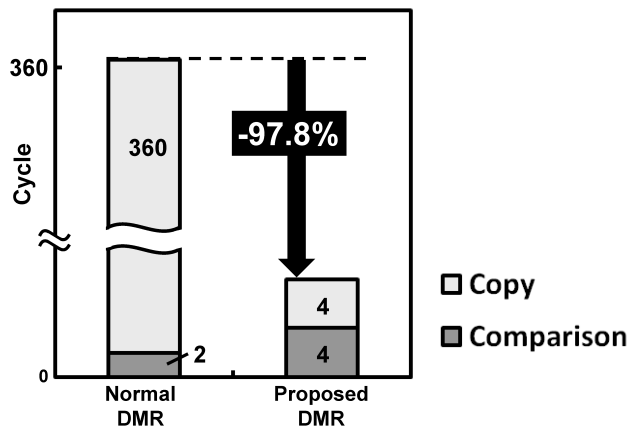


Fig. 7 Measured copy cycle, where the number of working registers is 360.

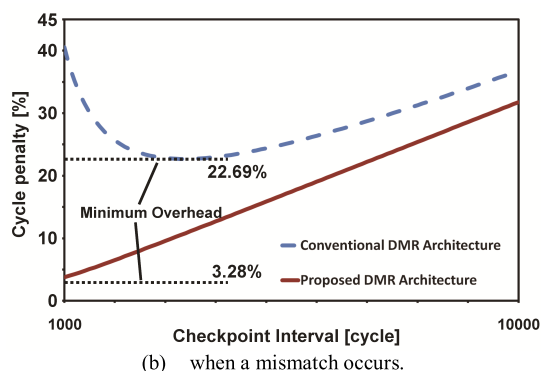
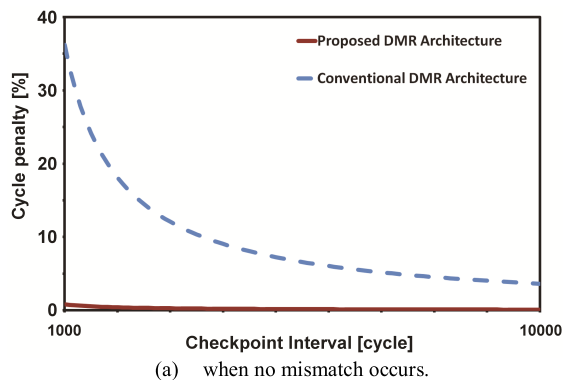


Fig. 8 Cycle penalty with respect to the checkpoint interval.

ing that the processor have 15 banks [14], in each of which the number of registers is 24, the number of registers is set to 360 here. The conventional DMR produces a comparison using CRC. Thereby it takes two cycles to compare CRCs. However, instantaneous comparison requires four cycles. Although copying between the registers via a shared bus requires 360 cycles, it takes four cycles to copy using an SRAM with simultaneous copy function: the conventional DMR architecture requires 362 cycles in the DMR phase. In contrast, the proposed architecture requires eight cycles for comparison and copy and reduces clock cycles by 97.8% compared to conventional copying via the shared bus.

In Fig. 8(a) and 8(b), the y-axis shows the cycle penalty with the checkpoint recovery approach; the x-axis shows the checkpoint interval, which is the number of cycles between two consecutive checkpoints. A collision detection for airbag system is performed every 1 ms [15], and pressure sensor system for the detection of side crashes transmits the pressure data every 500 μ s [16]. Assuming that the execution time of the task is 500 μ s, and that one cycle time is 16 ns because the operation frequency of ordinary automotive embedded processor is set to 62.5 MHz [13], then Fig. 8(a) presents the cycle penalty in the execution of a task that is fault-free. Figure 8(b) shows the case in which a fault occurs in executing the task once. In Fig. 8 (a), as the checkpoint interval decreases, the cycle penalty increases rapidly because comparison and copy are performed frequently. In the proposed architecture, the cycle penalty increases slightly when the checkpoint period is short because the proposed architecture dramatically reduces the cycle overhead in the copy operation. When the checkpoint interval increases, both the cycle penalties of conventional and proposed architectures are low. However, if a fault occurs in the working register and the comparison result indicates a mismatch, then the DMR controller must control cores so that a rollback is performed. Figure 8(b) shows that the cycle penalty increases as the checkpoint interval lengthens because the reexecution time is proportional to the checkpoint interval. The minimum cycle penalties of the conventional DMR and the proposed DMR are 22.6% and 3.28%, respectively, in this case.

Figure 9 shows the cycle penalty when multiple mismatches occur. The number of mismatches stands for the number of times that a comparison result indicates a mis-

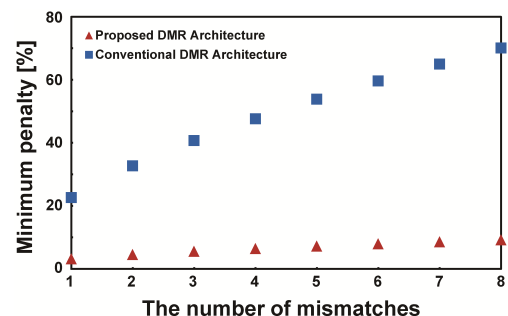


Fig. 9 Cycle penalty when multiple mismatches occur.

match while executing a task, which is equal to the number of times that a rollback is done. As the figure shows, the conventional DMR requires a larger cycle penalty under more frequent soft errors or stronger power supply noise. However, the proposed DMR can keep the minimum cycle penalty low, even if the rollback is performed numerous times. We assume that the checkpoint interval is set to the optimal checkpoint interval for each number of mismatches. Table 1 presents the optimal checkpoint intervals when the number of mismatches is varied. In the proposed DMR, the optimal checkpoint interval is much smaller than that of the conventional DMR. The cycle penalty is given by Eq. (1) as shown below.

$$\text{cycle penalty} = \left(\frac{T_{DMR}}{T_{checkpoint}} + N \times \frac{T_{DMR} + T_{checkpoint}}{T_{task}} \right) \times 100 \quad (1)$$

Therein, T_{DMR} stands for a cycle count overhead in the DMR phase, $T_{checkpoint}$ signifies a cycle count of the checkpoint interval, T_{task} denotes an execution cycle count of the task with fault free, and N represents the number of mismatches. If the checkpoint interval of the proposed DMR is set as 500 cycles, then the cycle penalty is 14.6% when a mismatch occurs eight times. However, in the conventional DMR, the respective optimal checkpoint intervals differ remarkably from one another, so it is difficult to get closer to a minimum cycle penalty. For example, if the checkpoint interval is set to be 3363 cycles, which is the optimal interval when a mismatch occurs, then the cycle penalty is 106% when a mismatch occurs eight times. Consequently, the proposed architecture is suitable for real-time systems because it can keep the cycle penalty lower.

4.2 Success Probability

We evaluate the success probability versus the fault rate, which is the probability with which a transient fault occurs. The success probability indicates the probability of task completion within its deadline time. We used the simulation method with a Markov model and Poisson process presented in an earlier report of the literature [12]. This method requires some parameters. Letting E be the execution time, and letting N be the number of checkpoints, then the relation among N , E and $T_{checkpoint}$ is written as follows.

$$N = \frac{E}{T_{Checkpoint}} \quad (2)$$

Letting D be the deadline time of the task and letting t_{DMR} be the checkpoint overhead time required for the DMR phase, then, in this simulation, the execution time of the task and deadline time of the task are $E = 1$ and $D = 2$, respectively, for the number of checkpoints $N = 10$. The checkpoint overhead in the conventional architecture is $t_{DMR} = 0.0116$; that in the proposed architecture is $t_{DMR} = 0.000128$. Figure 10 shows the success probability versus the fault rate. In the conventional architecture, the fault rate increase lowers the

Table 1 Optimal checkpoint interval that minimizes the cycle penalty.

# of mismatches	Optimal Checkpoint interval [cycle]	
	Proposed DMR	Conventional DMR
1	500	3363
2	354	2378
3	289	1941
4	250	1682
5	224	1504
6	204	1373
7	189	1271
8	176	1189

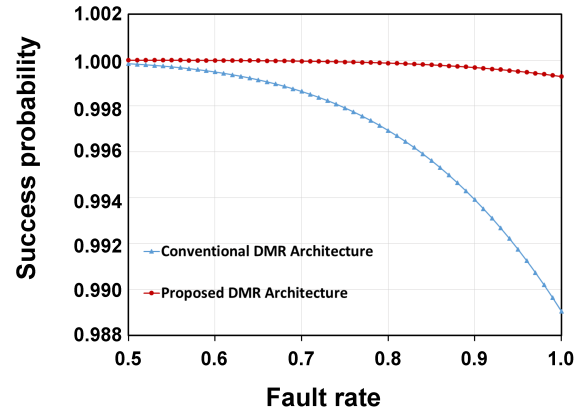


Fig. 10 Success probability with respect to fault rate.

probability of success. However, in the proposed architecture, the success probability decreases only slightly. Consequently, this simulation shows that the success probability is improved considerably using the proposed architecture.

5. Conclusion

We proposed a DMR architecture that can conduct an instantaneous comparison and a simultaneous copy scheme using the novel SRAM cell configuration. The proposed DMR architecture performs high-speed copying using a simultaneous copy scheme and low power comparison using an instantaneous comparison. The proposed architecture can execute operations with low latency even if the checkpoint interval becomes short. Consequently, the proposed DMR architecture provides benefits for real-time systems.

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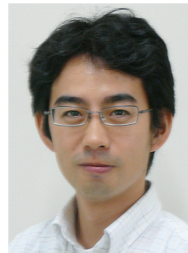
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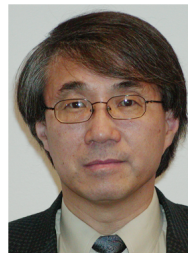
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